

Electronic & Technical Glasses

Passivation Glasses

Description: Ferro's Pb-Si-Al Passivation Glasses are designed for use on transistors, thyristors and diodes. These products are formulated and produced to achieve very low alkali and iron levels and can be applied by a variety of techniques including Doctor Blading, Photo-Spin, Sedimentation, Screen Printing and Electrophoresis.

Zinc-Boro-Silicate passivation glasses are used for hermetic passivation of high voltage diodes, thyristors and transistors. They provide high junction temperatures and can be applied to wafers using electrophoresis and thick film methods. These products also possess low alkali and iron levels.

Ferro's Passivation Glasses are also used for encapsulation of rectifiers using glass beading application methods. IP745 is primarily used for single chip, low to medium voltage rectifiers. IX2443 and EG2730 are crystallizing glasses with thermal expansion closely matched to silicon for use on stacked-chip diodes for high voltage applications.

Pb-Si-Al Based Passivation Glasses								
	IP 740	IP 745	IP 760	IP 750	IP 770	IP 820	IP 830	IP 900
Composition Family	Pb-Si-B-Al	Pb-Si-B-Al	Pb-Si-B-Al	Si-Pb-B-Al	Pb-Si-Al	Pb-Si-Al	Pb-Si-Al-B	Si-Pb-B-Al
Glass Type	V	V	V	V	V	V	V	V
Peak Fire Temp (°C)	680	690	710	755	820	910	815	890
Time @ Peak Temp (mins)	10	10	10	10	15	15	15	15
CTE @ 260°C	51	48	48	42.5	45	46	45	37
CTE @ Set Pt	56	53.6	53.8	46.7	47	46	50	38.3
Softening Point	636	630	653	698	780	820	740	785
Та	490	478	505	500	620	650	571	540
Tg	465	458	475	462	596	632	544	520
DEN	3.89	3.45	3.52	3.29	3.8	3.8	3.54	2.86
Typical Powder Form	RWG	DSD, REG, RWG	TF, REG, RWG	TF, REG, RWG	TF, RWG	REG, RWG	TF, RWG	TF, RWG
Typical Application	Wafer Passivation	Diode Encapsulation	Wafer Passivation	Wafer Passivation	Wafer Passivation	Wafer Passivation	Wafer Passivation	Wafer Passivation

V Vitreous

D Crystallising

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Passivation Glasses

Zn-B-Si-Pb Based Passivation Glasses IX 2218 IX 2683 IX 2443 EG 2730 Product Group Passivation Passivation Passivation Passivation Zn-B-Si-Pb Zn-B-Si-Pb Zn-B-Si-Pb Zn-B-Si-Pb **Composition Family** Glass Type V V D D Peak Fire Temp (°C) 670 690 700 720 Time @ Peak Temp 10 10 10 10 (mins) CTE @ 260°C 44 48 45 45 CTE @ Set Pt 55 33.0* 37.0* 56.9 Softening Point 612 635 618 615 580 Та 542 542 550 Тg 525 560 531 538 DEN 4.03 3.85 3.96 3.9 DSD Typical Powder Form REG RWG, DSD TF Typical Application HV Diode encapsulant Wafer Passivation **Diode Encapsulation Diode Encapsulation**

V Vitreous

D Crystallising

Fired Thermal Expansion

For applications requiring thicker layers or on large diameter wafers, composite "L" and "C" versions are available for most products. The addition of low expansion inert fillers generally produce thermal expansions 10-15% lower than the base glass, providing a closer expansion fit to the silicon wafer. This typically requires a 25C higher firing temperature. Composites such as these are typically not suitable for direct application on the junction and so an underlying layer of the glass is recommended.

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